

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|---|---|------------------|---------|------------------|
| L6 | 25444 | (reference with voltage) and (latch (flip with flop)) and comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 12:58 |
| L7 | 6978 | (reference with voltage) same (latch (flip with flop)) same comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 12:55 |
| L8 | 2393 | (reference with voltage) with (latch (flip with flop)) with comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 12:55 |
| L9 | 16977 | (reference with voltage) and (flip with flop) and comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 12:56 |
| L10 | 4463 | (reference with voltage) same (flip with flop) same comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:06 |
| L11 | 1475 | (reference with voltage) with (flip with flop) with comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:14 |
| L12 | 2 | (reference with voltage) with (flip with flop) with comparator with (decouple decoupling decoupler) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 12:57 |
| L13 | 18551 | (reference adj voltage) and (latch (flip with flop)) and comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 12:59 |

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| L14 | 5440 | (reference adj voltage) same (latch (flip with flop) flipflop) same comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:00 |
| L15 | 1847 | (reference adj voltage) with (latch (flip with flop) flipflop) with comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:01 |
| L16 | 3 | (reference adj voltage) with (latch (flip with flop) flipflop) with comparator with (decouple decoupling decoupler decoupled) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:03 |
| L26 | 3091 | ((test testing) with (chip circuit ic dut)) and (reference) and cell and comparator and (latch flipflop (flip adj flop)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:54 |
| L27 | 398 | ((test testing) with (chip circuit ic dut)) and (reference) and cell and comparator and (latch flipflop (flip adj flop)) and (decouple decoupling decoupler) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:28 |
| L28 | 23 | ((test testing) with (chip circuit ic dut)) and (reference) and (cell same comparator same (latch flipflop (flip adj flop))) and (decouple decoupling decoupler) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:29 |
| L29 | 1188 | ((test testing) with (chip circuit ic dut)) and (reference adj (voltage input)) and cell and comparator and (latch flipflop (flip adj flop)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:35 |
| L30 | 421 | ((test testing) with (chip circuit ic dut)) and (reference adj (voltage input)) and comparator and (latch flipflop (flip adj flop)) and (decouple decoupling decoupler decoupled) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:36 |

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| L31 | 392 | ((test testing) with (chip circuit ic dut)) and (reference adj (voltage input)) and ((test supply) with voltage) and comparator and (latch flipflop (flip adj flop)) and (decouple decoupling decoupler decoupled) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:38 |
| L32 | 5 | ((test testing) with (chip circuit ic dut)) and ((reference adj (voltage input)) same ((test supply) with voltage) same comparator same (latch flipflop (flip adj flop))) and (decouple decoupling decoupler decoupled) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:47 |
| L34 | 20639 | (comparator with ((flip with flop) flipflop)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:48 |
| L35 | 4630 | comparator same ((flip with flop) flipflop) same (reference with voltage) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:52 |
| L36 | 15 | comparator same ((flip with flop) flipflop) same (reference with voltage) same (decoupling decouple decoupler decoupled) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:49 |
| L37 | 4149 | comparator same output same ((flip with flop) flipflop) same (reference with voltage) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:53 |
| L38 | 1015 | comparator with output with ((flip with flop) flipflop) with (reference with voltage) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:54 |
| L39 | 1 | ((test testing) with (chip circuit ic dut)) and (comparator with output with ((flip with flop) flipflop) with (reference with voltage)) and (decoupling decoupler decouple decoupled) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 13:57 |

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| L40 | 39 | ((test testing) with (chip circuit ic dut)) and (comparator with output with ((flip with flop) flipflop) with (reference with voltage)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 14:38 |
| L41 | 1 | ((test testing) with (chip circuit ic dut)) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage) (under with voltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage) (over with voltage))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 14:41 |
| L42 | 5 | ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage) (under with voltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage) (over with voltage))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 14:45 |
| L43 | 0 | ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage) (under adj voltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage) (over adj voltage))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 14:42 |
| L44 | 0 | ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 14:46 |
| L45 | 22 | (comparator with output with ((flip with flop) flipflop) with (reference with voltage)) and (comparator same ((undervoltage) (under with voltage))) and (comparator same ((overvoltage) (over with voltage))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 15:03 |

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| L46 | 2 | (comparator with output with ((flip with flop) flipflop) with (reference with voltage)) and (comparator same ((undervoltage))) and (comparator same ((overvoltage))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 14:50 |
| L47 | 161 | (Ernest with Allen) (David with Castaneda) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 15:04 |
| L48 | 1 | 47 and ((flipflop) latch (flip with flop)) and comparator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/02/14 15:06 |

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PLUS Search Results for S/N 10700790, Searched February 14, 2005

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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